

Application/Control No.	Control No. Applicant(s)/Patent under Reexamination	
10/805,890	NALLAN ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

SEARCHED					
Class	Subclass	Date	Examiner		
216	58	4/11/2006	ВТ		
216	68	4/11/2006	вт		
438	722	4/11/2006	ВТ		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Update search using USPAT, USPG- PUB, JPO, EPO, DERWENT databases	4/11/2006	ВТ